

## **MOSFET**

## **StrongIRFET™ 2 Power-Transistor**

#### **Features**

- Optimized for a wide range of applications
  N-Channel, normal level
  100% avalanche tested

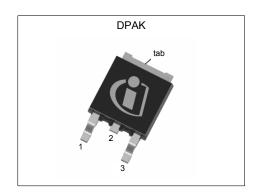
- Pb-free lead plating; RoHS compliant
  Halogen-free according to IEC61249-2-21

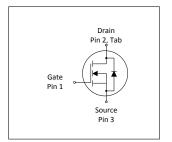
### **Product validation**

Qualified according to JEDEC Standard

Table 1 **Key Performance Parameters** 

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Parameter	Value	Unit					
<b>V</b> <sub>DS</sub>	80	V					
R <sub>DS(on),max</sub>	4.0	mΩ					
I <sub>D</sub>	129	A					
Qoss	65	nC					
Q <sub>G</sub>	54	nC					











Type / Ordering Code	Package	Marking	Related Links
IPD040N08NF2S	PG-TO252-3	040N08NS	-

# StrongIRFET<sup>TM</sup> 2 Power-Transistor IPD040N08NF2S



## **Table of Contents**

Description	1
Maximum ratings	3
Thermal characteristics	3
Electrical characteristics	4
Electrical characteristics diagrams	6
Package Outlines	0
Revision History	1
Trademarks 1	1
Disclaimer	1

## StrongIRFET<sup>™</sup> 2 Power-Transistor IPD040N08NF2S



## 1 Maximum ratings at $T_A$ =25 °C, unless otherwise specified

Table 2 Maximum ratings

Davamatar	0		Value	s		
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Continuous drain current <sup>1)</sup>	I <sub>D</sub>	- - -	- - -	129 98 82 20	A	V <sub>GS</sub> =10 V, T <sub>C</sub> =25 °C V <sub>GS</sub> =10 V, T <sub>C</sub> =100 °C V <sub>GS</sub> =6 V, T <sub>C</sub> =100 °C V <sub>GS</sub> =10V, T <sub>A</sub> =25 °C, R <sub>thJA</sub> =50 °C/W <sup>2</sup> )
Pulsed drain current <sup>3)</sup>	I <sub>D,pulse</sub>	-	-	516	Α	T <sub>C</sub> =25 °C
Avalanche energy, single pulse <sup>4)</sup>	<b>E</b> AS	-	-	112	mJ	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 $\Omega$
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-
Power dissipation	P <sub>tot</sub>	-	-	150 3.0	W	T <sub>C</sub> =25 °C T <sub>A</sub> =25 °C, R <sub>thJA</sub> =50 °C/W <sup>2)</sup>
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55	-	175	°C	-

#### 2 Thermal characteristics

Table 3 Thermal characteristics

Dovemeter	Cumbal	Values			Unit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	1.0	°C/W	-
Thermal resistance, junction - ambient, 6 cm² cooling area²)		-	-	50	°C/W	-
Thermal resistance, junction - ambient, minimal footprint	R <sub>thJA</sub>	-	-	75	°C/W	-

<sup>&</sup>lt;sup>1)</sup> Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.  $^{2)}$  Device on 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain

connection. PCB is vertical in still air.

3) See Diagram 3 for more detailed information

4) See Diagram 13 for more detailed information

## StrongIRFET<sup>™</sup> 2 Power-Transistor IPD040N08NF2S



### 3 Electrical characteristics

at T<sub>j</sub>=25 °C, unless otherwise specified

**Table 4** Static characteristics

D	0		Value	s	1114		
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	80	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	
Gate threshold voltage	V <sub>GS(th)</sub>	2.2	3.0	3.8	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =85 μA	
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.1 10	1 100	μΑ	V <sub>DS</sub> =80 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =80 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	
Gate-source leakage current	I <sub>GSS</sub>	-	10	100	nA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	3.4 4.4	4.0 5.7	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =70 A V <sub>GS</sub> =6 V, I <sub>D</sub> =35 A	
Gate resistance	R <sub>G</sub>	-	1.9	-	Ω	-	
Transconductance <sup>1)</sup>	<b>g</b> fs	60	-	-	S	$ V_{DS}  \ge 2 I_D R_{DS(on)max}, I_D = 70 A$	

Table 5 Dynamic characteristics

Devementar	Cumbal	Values			11:4	Nata / Tank Oam distant
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Input capacitance	C <sub>iss</sub>	-	3800	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =40 V, f=1 MHz
Output capacitance	Coss	-	620	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =40 V, f=1 MHz
Reverse transfer capacitance	C <sub>rss</sub>	-	29	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =40 V, f=1 MHz
Turn-on delay time	$t_{\sf d(on)}$	-	14	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =70 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Rise time	t <sub>r</sub>	-	54	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =70 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Turn-off delay time	$t_{ m d(off)}$	-	28	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =70 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Fall time	t <sub>f</sub>	-	13	-	ns	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =70 A, $R_{\rm G,ext}$ =1.6 $\Omega$

Table 6 Gate charge characteristics<sup>2)</sup>

Parameter	Cumbal	Values			Unit	Note / Test Condition
Farameter	Symbol	Min.	Тур.	Max.	Ullit	Note / Test Condition
Gate to source charge	Q <sub>gs</sub>	-	18.3	-	nC	$V_{DD}$ =40 V, $I_{D}$ =70 A, $V_{GS}$ =0 to 10 V
Gate charge at threshold	Q <sub>g(th)</sub>	-	11.4	-	nC	V <sub>DD</sub> =40 V, I <sub>D</sub> =70 A, V <sub>GS</sub> =0 to 10 V
Gate to drain charge	Q <sub>gd</sub>	-	11.8	-	nC	V <sub>DD</sub> =40 V, I <sub>D</sub> =70 A, V <sub>GS</sub> =0 to 10 V
Switching charge	Q <sub>sw</sub>	-	18.7	-	nC	V <sub>DD</sub> =40 V, I <sub>D</sub> =70 A, V <sub>GS</sub> =0 to 10 V
Gate charge total <sup>1)</sup>	Qg	-	54	81	nC	V <sub>DD</sub> =40 V, I <sub>D</sub> =70 A, V <sub>GS</sub> =0 to 10 V
Gate plateau voltage	V <sub>plateau</sub>	-	4.8	-	V	V <sub>DD</sub> =40 V, I <sub>D</sub> =70 A, V <sub>GS</sub> =0 to 10 V
Output charge	Qoss	-	65	-	nC	V <sub>DS</sub> =40 V, V <sub>GS</sub> =0 V

 $<sup>^{1)}</sup>$  Defined by design. Not subject to production test.  $^{2)}$  See "Gate charge waveforms" for parameter definition

# StrongIRFET<sup>TM</sup> 2 Power-Transistor IPD040N08NF2S

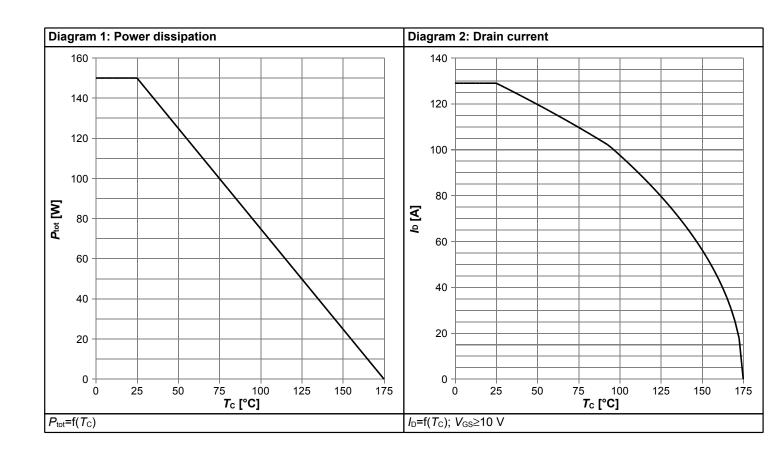


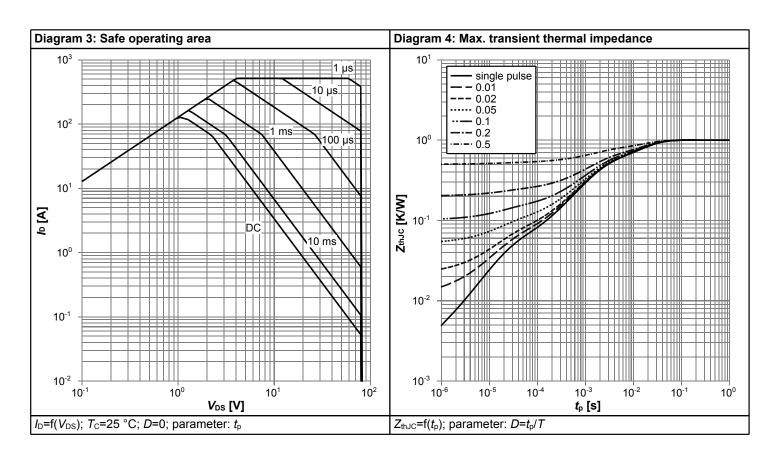
### Table 7 Reverse diode

Developed	Cumbal		Values			Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continuous forward current	Is	-	_	103	Α	T <sub>C</sub> =25 °C	
Diode pulse current	I <sub>S,pulse</sub>	-	-	516	Α	T <sub>C</sub> =25 °C	
Diode forward voltage	V <sub>SD</sub>	-	0.92	1.2	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =70 A, T <sub>j</sub> =25 °C	
Reverse recovery time	t <sub>rr</sub>	-	33	-	ns	V <sub>R</sub> =40 V, I <sub>F</sub> =70 A, di <sub>F</sub> /dt=500 A/μs	
Reverse recovery charge	Qrr	-	189	_	nC	$V_R$ =40 V, $I_F$ =70 A, $di_F/dt$ =500 A/ $\mu$ s	

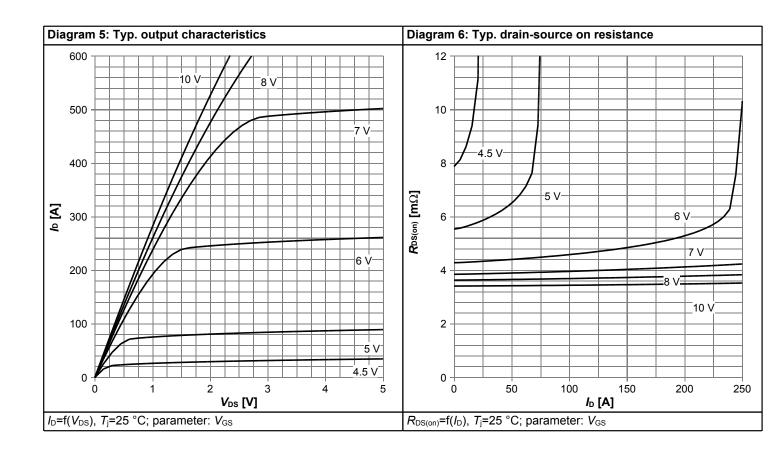


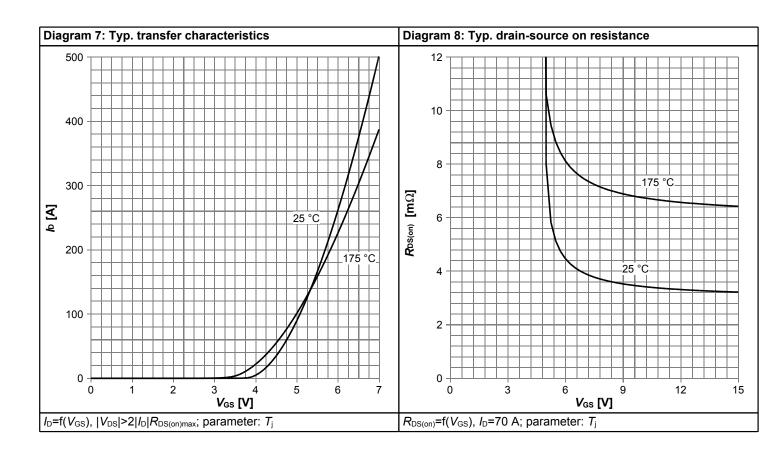
## 4 Electrical characteristics diagrams



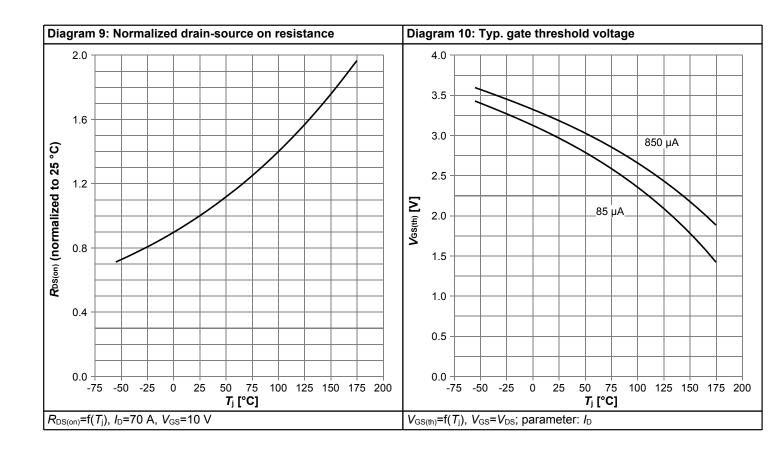


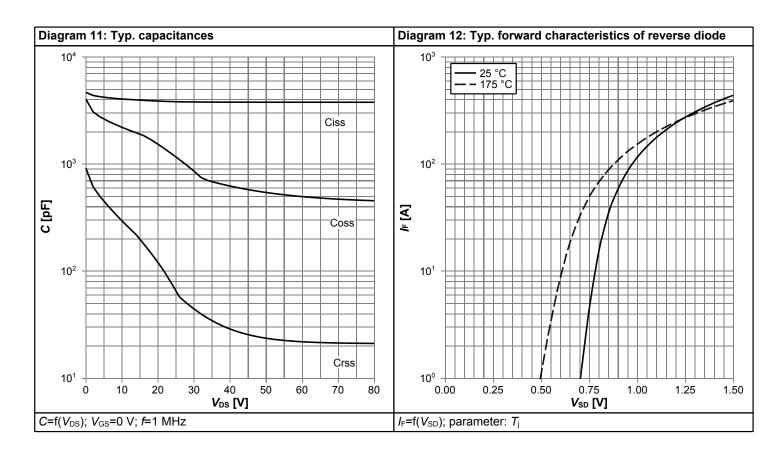




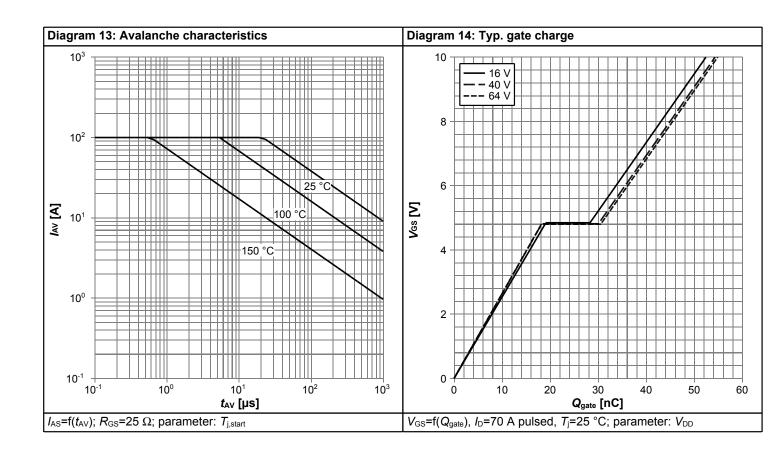


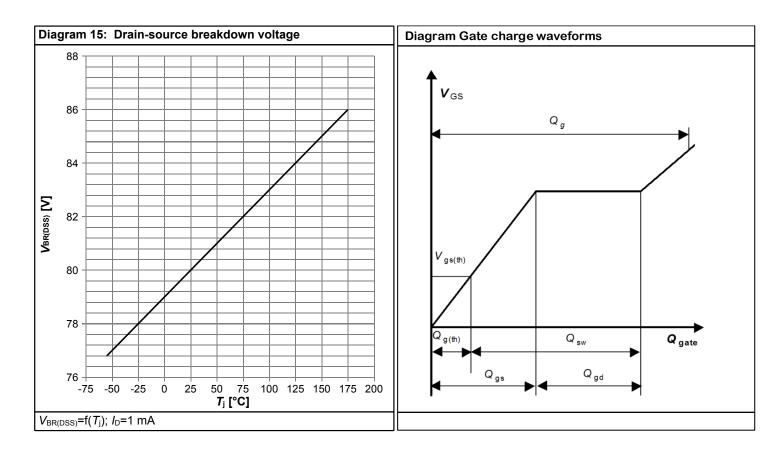






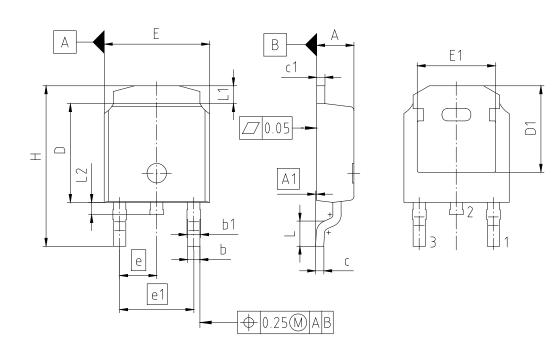








## 5 Package Outlines



PACKAGE - GROUP NUMBER:	PG-TO2	PG-TO252-3-U01					
DIMENSIONS	MILLIMETERS						
DIMENSIONS	MIN.	MAX.					
Α	2.18	2.39					
A1	0.00	0.13					
b	0.64	0.89					
b1	0.76	1.14					
С	0.46	0.61					
c1	0.40	0.89					
D	5.97	6.22					
D1	5.21						
E	6.35	6.73					
E1	4.32						
е	2.	29					
e1	4.	4.58					
N	3						
Н	9.40	10.41					
L	1.40	1.78					
L1	0.89	1.27					
L2	0.50	1.02					

Figure 1 Outline PG-TO252-3, dimensions in mm

## StrongIRFET<sup>™</sup> 2 Power-Transistor



#### **Revision History**

IPD040N08NF2S

Revision: 2022-10-10, Rev. 2.2

Previous Revision

Revision	Date Subjects (major changes since last revision)					
2.0	2022-02-08	Release of final version				
2.1	2022-06-22	Update Diagram 15				
2.2	2022-10-10	Update package outline drawing				

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